

LIU-BWS electronics & systems

15.09.2020 J. Emery

D. Belohrad, J. Esteban Felipe, A. Goldblatt, G. Lacarrere, M. Nieto, F. Roncarolo, C. Schillinger, J. Tassan-Viol

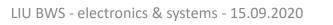


- 1. Installations
- Individual System Tests (IST) 2. BWSIDC (Intelligent drive crate) Design status and qualification 3. Position (Resolver) Acquisition and Production and test tools 4. Supervision crate (BWSASC) 5. Firmware Power Particle beam Position (Optical Losses M-PMT



BWS-LIU Installations

- Mechanics ready in PSB and PS, partially missing in the SPS
- PSB tunnel cablings done & tested (Aurelie, Jean, Guillaume, Jose)
- PS On-going tunnel cabling this week (Guillaume, Jose)
- SPS to start next
- Surface installations are waiting for our electronics (IDC drives, MPMT amplifiers, VFC-HD+ADC)







BWS-LIU Installations

INSTA	LLATION S	TATUS 15.09.	.2020			TUNNEL					SURFACE		
Machine		Orientation	Ring	cables	fibers	mechanism	mpmt	patchbox	idc drive	amp	vfc+adc	ISEG	cabling
	4L1	Н	R1	ready					not installed				partial
	4L1	Н	R2			not moving							
	4L1	Н	R3										
PSB	4L1	Н	R4										
ď	11L1	V	R1										
	11L1	V	R2										
	11L1	V	R3										
	11L1	V	R4										
	54	н		ready		not tested	sig. cables	not installed					
	64	V					missing						
PS	65	Н											
	68	Н											
	85	V											
	41677	V		ready	not installed								
SPS	41678	V											
SI	51638	Н											
	51639	Н											

BWS-LIU Individual System Test

- New system able to discover issues of resolver, motor or cabling without need of dummy scanner in the tunnel (OPEN LOOP TEST).
- Test procedure for the drive related function automatized. Includes open loop tests, scans, wire check, etc. Uses python scripts (library for the IDC), eventually part will be integrated to FW
- PSB 7 out of 8 mechanism operated at nominal speed (20m/s) using the same IDC controller with local link (python).
- <u>One scanner mechanism to be exchanged</u>
- PSB Acquisition installation successfully tested manually by Aurelie/Guillaume
- Acquisition test will be automatized ones we have full system installed (MPMT amplifier + VFC-HD + ADC)

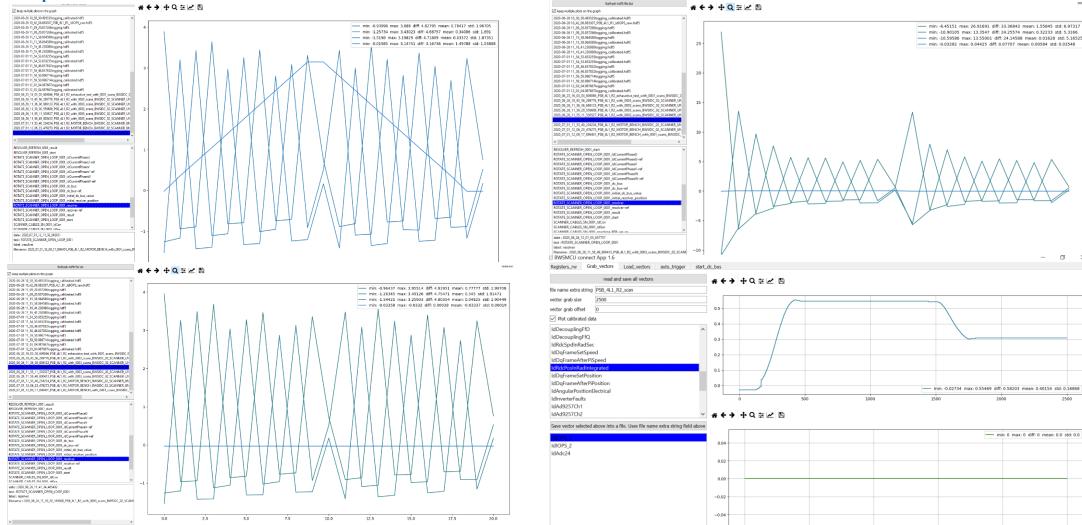


BWS-LIU Individual System Test

Individual	nosition	Orientation	Ring	Asset Mechanism Asset Mechanism deduced from the electronics SN	Electronic	ESN decoded	cables electronic	control	Dummy scanner	open loop rotation	scans	Optical	wire check	MPMT	patch cords	MPMT surface
System Tests	position	Onentation	Ning	(from the surface)	SN (ESN)	ESIN decoded	check	patchcord install	test	open loop rotation	@140 rad/s	encoder	WITE CHECK	assembly	HV+SIG	test
	4L1	Н	R1	PXBWSRA005-CR000010	74	PSB_0_10	9				6		to check			
	4L1	Н	R2	PXBWSRA005-CR000007	71	PSB_0_07	9			can't move	-		to check			
	4L1	Н	R3	PXBWSRA005-CR000008	72	PSB_0_08	9				4		to check			
PSB	4L1	Н	R4	PXBWSRA005-CR000005	69	PSB_0_05	9				10		to check			
l a	11L1	V	R1	PXBWSRA005-CR000004	68	PSB_0_04	9				18		to check			
	11L1	V	R2	PXBWSRA005-CR000009	73	PSB_0_09	9				14		to check			
_	11L1	V	R3	PXBWSRA005-CR000006	70	PSB_0_06	9				13		to check			
	11L1	V	R4	PXBWSRA005-CR000003	67	PSB_0_03	9				13		to check			
	54	Н														
	64	V														
P S	65	Н														
	68	H														
	85	V														
-	41677	V														
SPS	41678	V														
N N	51638	Н														
	51639	H														



Individual system tests (IST) PS Booster – 4L1-R2

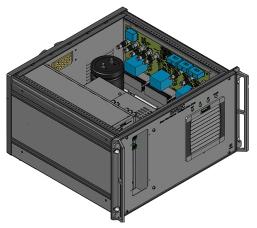


LIU BWS - electronics & systems - 15.09.2020

Save vector selected above into a file. Uses file name extra string field above



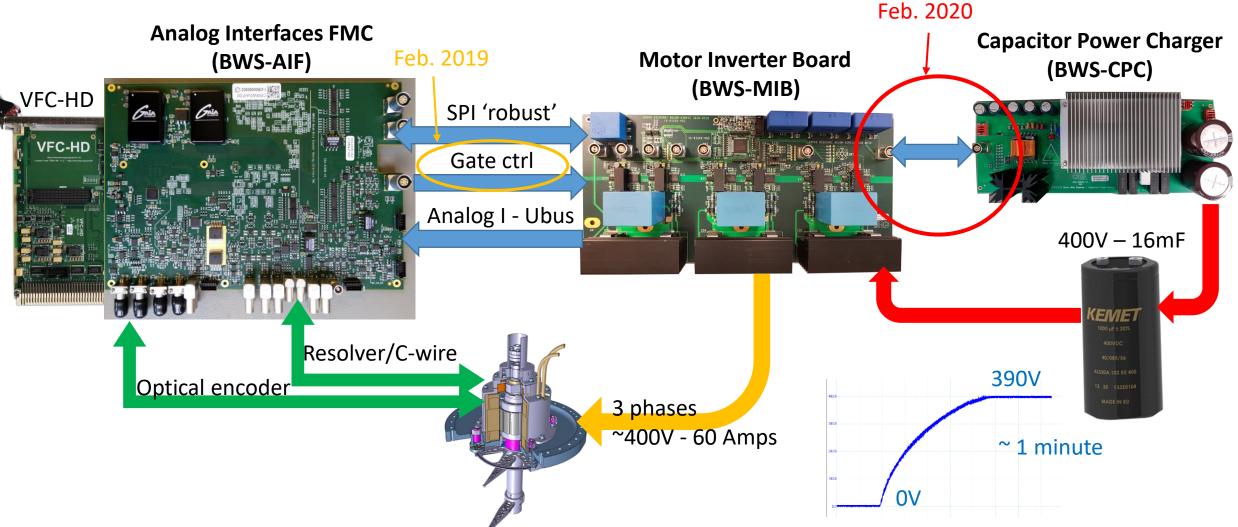
- Power boards issues (Jan-Feb 2020) fixed and pre-production corrected Thanks to Miguel, Ervin and Guillaume to solve this issue
- IDC drive extensive validation performed during confinement
 24 April 22 June more than 13'000 scans with various temperature 23-55 [°C]
- Final designs modifications & go-ahead PCB production (June 2020)
- Go-ahead PCB assemblies (July 2020) after additional tests





Intelligent Drive Crate (IDC) architecture



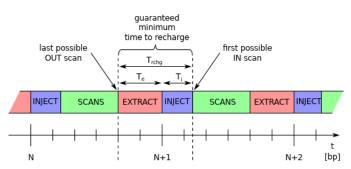


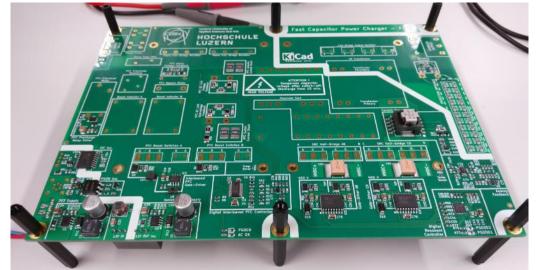
LIU BWS - electronics & systems - 15.09.2020



- Redesign of the charger for future upgrade by (E. Mazlagic - Tech. Student mostly TW)
- Solution to increase repeatability rate
- "Fast Capacity Power Charger" using an efficient power stage topology
- Designed to replace existing charger (same mechanical and electrical interfaces)
- Prototype under test at Tech. University of Lucerne (CH)
- Plan to test inside an IDC drive at CERN before end of February 2021 (end of Master thesis)

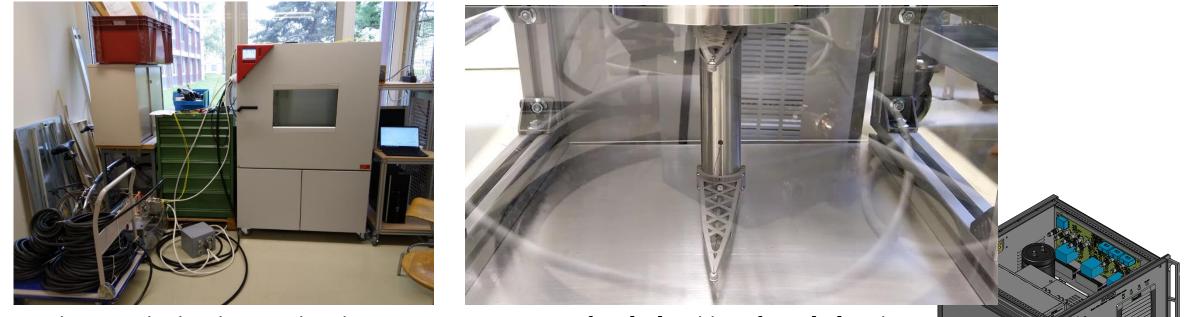
slot		value	unit
basic period	T_{bp}	1'200	ms
injection	T_i	275	\mathbf{ms}
scan	T_s	670	\mathbf{ms}
extraction	T_e	395	\mathbf{ms}
recharge	T_{rchq}	670	\mathbf{ms}







IDC drive extensive validation performed at CERN during lockdown
 24 April – 22 June – more than 13'000 scans at various temperature 23-55 [°C]



IDC drive inside the climatic chamber at top temperature of 55 [°C], cables of 120 [m] and high repetition rate of 5 scans at 20 [m/s] every ~15s.



IDC drive extensive validation performed during lockdown
 24 April – 22 June – more than 13'000 scans at temperature between 23-55 [°C]

date	location	SN IDC	SN scanner	duration (h)	temperature	scan per cycle	cycle duration	nbr cycles	nbr scans	charge- discharge cycles	remarques
7.05		IDC_01	ESS-CR014	2.113194444	25	1	8.5	895	895		
7.05		IDC_01	ESS-CR014	1.43	25	2	13	396	792		
8.05		IDC_01	ESS-CR014	1.843333333	25	3	14	474	1422		
8.05		IDC_01	ESS-CR014	0.237222222	25	3	14	61	183		
12.05		IDC_01	ESS-CR014	0.263888889	30	3	10	95	285		
12.05		IDC_01	ESS-CR014	0.91	40	5	12	273	1365		
13.05		IDC_01	ESS-CR014	0.725833333	40	5	13	201	1005		
13.05		IDC_01	ESS-CR014	1.216944444	50	5	13	337	1685		
14.05		IDC_01	ESS-CR014	1.144722222	55	5	13	317	1585		
15.05		IDC_01	ESS-CR014	2	55					50	
19.05		IDC_02	ESS-CR013	0.666	25					14	
20.05		IDC_02	ESS-CR013		25	1	6.5	29	29		
22.05		IDC_02	ESS-CR013	0.28	23	3	10.3	101	303		top speed reach 150 rad/s!
27.05	ClimCham	IDC_01	ESS-CR014		23	1	15s	202	202		
27.05	Wslab	IDC_02	ESS-CR013		23	1	15s	200	200		
28.05	Wslab	IDC_02	ESS-CR012		23	1	15s	175	175		rwire=4,27kOhm / isolation=open
29.05	Wslab	IDC_02	ESS-CR012		23	1	15s	330	330		rwire=4,27kOhm / isolation=open
3.06	Wslab	IDC_02	ESS-CR012	0.5	23	1	9	211	211		wire and isolation ok
3.06	Wslab	IDC_02	ESS-CR012	2.1	23	3	15	551	1653		wire and isolation fault
4.06	Wslab	IDC_02	ESS-CR011		23	3		104	312		wire and isolation after 1 scan
12.06	Wslab	IDC_02	ESS-CR011		23	1		80	80		full automated scripts / tests data into same hdf5 file
15.06	ClimCham	IDC_02	ESS-CR010		40	3	9	130	390		100m cable, use gui, DC_BUS stable at around 310V
17.06	ClimCham	IDC_02	ESS-CR010		55	1		100	100		100m cable, script, minimal data taking
17.06	ClimCham	IDC_02	ESS-CR010		55	1		10	10		100m cable, script, minimal data taking, better IOPS settings
22.06	867	IDC_01	ESS-CR009		25	1		20	20		220m cables, script, Gain current = 6 (was2), minimal data, noisy
22.06	867	IDC_01	ESS-CR009		25	1		20	20		220m cables, script, Gain current = 3 (was2), good behaviour, IOPS noise
total								5292	13232		



Production and test tools - Control





- Production & Test lab ready for the series before lock-down Christiane, Guillaume, Georges and Thasos (BL Greek team).
- Help from Miguel and Jose during the lock-down. Christiane back mid-June.
- 10 pcs pre-series done
- 27 pcs series assembly finished waiting for the electronics board
- Expecting start boards testing on the 21 September

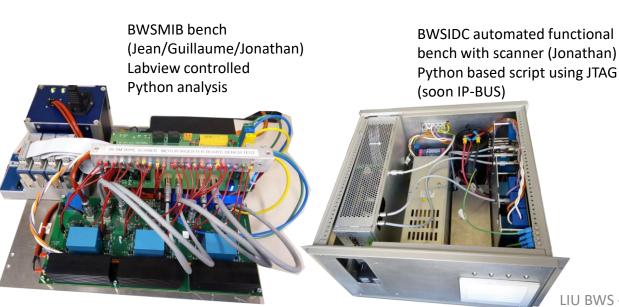


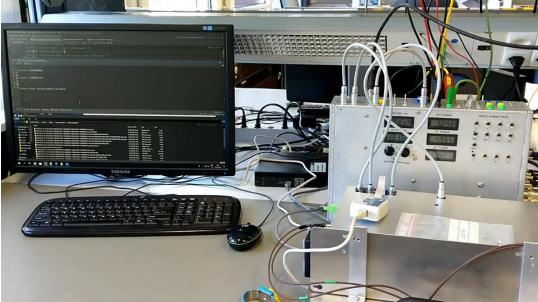




Production and test tools - Control

- Test bench for all boards, automated for the most complex
- Same scripts family used for the complete drive BWSIDC
- Enormous reduction in testing time at the cost of more developments
- Step 1: Resistive measurements & excel report
- Step 2: Automated tests & report generation per board
- Step 3: Data analysis of all boards results at ones







BWSAIF (Motor inverter) bench (Guillaume/Jonathan) Python based script using JTAG (soon to be migrated to IP-BUS)



Design and validation - Hardware Acquisition

- MPMT assembly Scintillator PMT/PCB board:

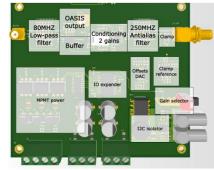
 Assembled and lab validated with laser source (Aurelie & BI-ML)
 Series assembled for PSB and PS
- MPMT amplifier:

 - kick-off meeting 7 April (Miguel)
 design review 5 June by William Vigano and al.
 - PCB version 2 tested & first crate assembled
 - Design drawing (electronics and mechanics) ready
 Production will be handled by TE-MPE (to be started)
- Fast ADC module:
 - validation and go-ahead for production end of February (David)
 First batch of 30pcs received beginning of June
 all pieces tested (Jose & David) results under analysis (Federico)

 - Next batch to be launched soon



MPMT board for 4 PMT EDA-03764



MPMT amplifier EDA-xxxxx

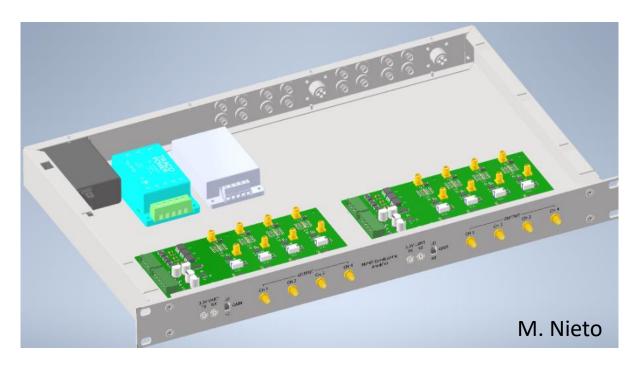


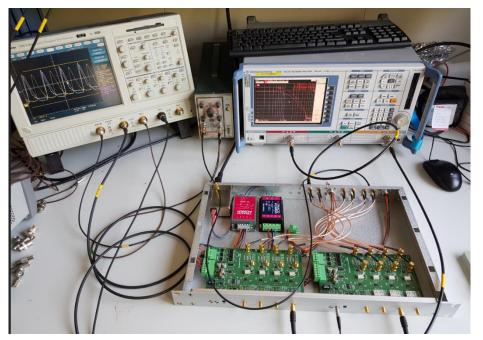
Commercial ADC 4x500MHz 14bits by I.A.M. Electronics



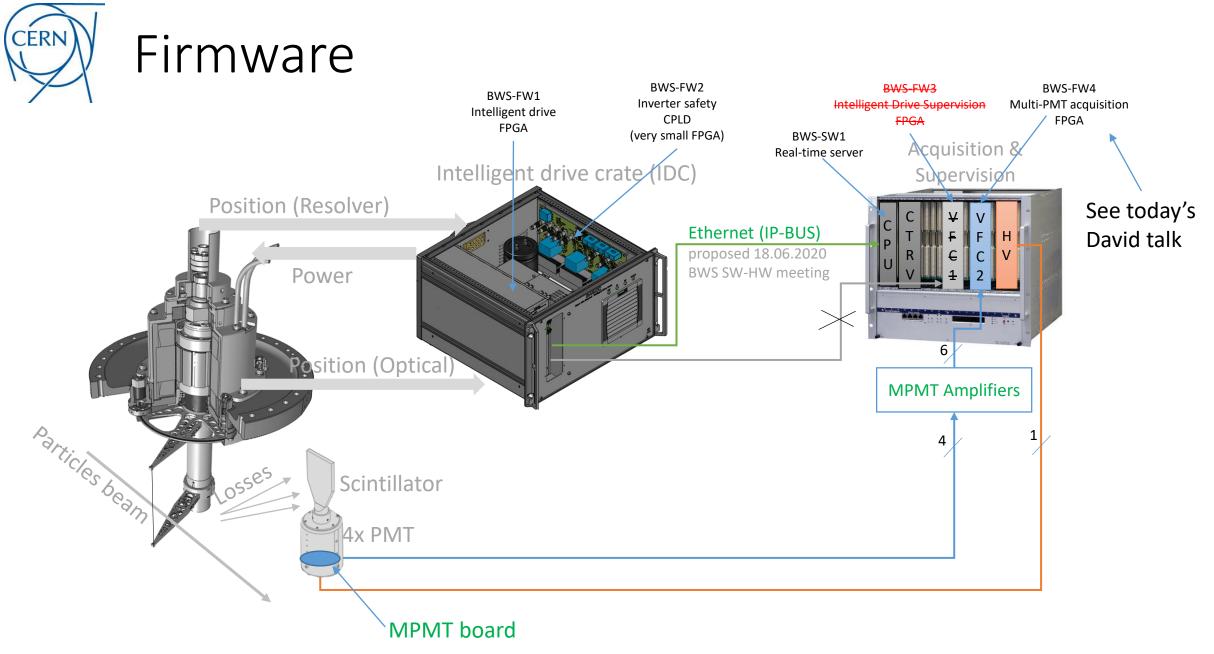
Design and validation - Hardware Acquisition

- MPMT amplifier:
 - Design drawing (electronics and mechanics) ready





Test setup of the MPMT amplifier V2



LIU BWS - electronics & systems - 15.09.2020



Firmware status

- <u>BWS-FW1 Intelligent drive FPGA</u> Optical encoder pre-processing + timing closure optimization (done during lockdown) IP-BUS link to the CPU (ready since last week) Movement sequencer (working on it) Multi-speeds (next) DDR memory integration (future)
- <u>BWS-FW2 Inverter safety CPLD</u> (very small FPGA) Operational on V2 boards being produced now Good for operation at nominal speed
- <u>BWS-FW3 Intelligent Drive Supervision FPGA</u> Not needed anymore in the new architecture
- <u>BWS-FW4 Multi-PMT acquisition FPGA</u> See David's presentation



Firmware – BWS-FW1 - IP-BUS link to SW

- Now integrates IP-BUS link
- Board answering to ping (1st September)
- 1Gigabit copper link
- IP address generated from unique number of the VFC-HD board
- Low level python driver written (python) for simple read and write transactions
- Python DevExpert app migrated
- Successful control of 4 IDC drive in the PSB connected to the same Ethernet switch (using DevExpert app)
- Setup ready in the lab with MEN-A25 and Ethernet mezzanine for SW to start testing it.

tance)
ance			Status	Enabled	LEs: 4464		4432 Small: I		Large: NA								
n a	uto_si	ignaltap_0	Not running		4464 cells	274432 bit	NA	NA	NA								
-		2020/09/01 15:01:5	0 (0:0:14.1 elapsed)										k to insert time:				
	Alias		Name			-128	-64	9	128	192	256	320	384	448	512	576	640
•			test ipbus_ctrl:ipbus er														
•			test ipbus_ctrt:ipbus ip			_											
•			test ipbus_ctrl:ipbus ip			_											
•			test ipbus_ctrl:ipbus ip			_			աաստաս	աստաստ							
•			test ipbus_ctrl:ipbus ip			_											
•			test ipbus_ctrl:ipbus ip			_		_			L						
•			test ipbus_ctrl:ipbus ip														
			test ipbus_ctrl:ipbus ip			_		_									
			test ipbus_ctrl:ipbus m														
			test ipbus_ctrl:ipbus m			-	1	-									
			test ipbus_ctrl:ipbus m			_											
			test ipbus_ctrl:ipbus m														
			test ipbus_ctrl:ipbus m			-											
-			test ipbus_ctrl:ipbus m			_											
			test ipbus_ctrl:ipbus m test ipbus_ctrl:ipbus m			_					_						
			test ipbus_ctrt:ipbus m test ipbus_ctrt:ipbus pl			-		1									
•			test[ipbus_ctrl:ipbus]pi														
•			test ipbus_ctrl:ipbus pr			_		-									
•			test[ipbus_ctrt:ipbus]R/			-											
			test ipbus_ctrl:ipbus rs														
			test[ipbus_ctrt:ipbus]rs														
•			test[ipbus_ctrl:ipbus]rs			_		-									
			us_test ipbus_ctrl:ipbus		01.01	-	00000h								0000000h		
			us_test ipbus_ctrl:ipbus us_test ipbus_ctrl:ipbus				00000n							0		00200440h	
-			us_test ipbus_ctrl:ipbus us_test ipbus_ctrl:ipbus				00480h		00200400h				1111111	1111111			π
			test av mm_chipselect		ne[oo]				002004000								
		IPBusVFC:ip bus				-											
			test[av_mm_read	*		-					mmm						
		IPBusVFC:ip_bus				-											
			us test av mm addres	\$32[31.0]		008	01200h				1111111					00801100h	
-			us_test av_mm_readda			-	00000h							0	0000000h		
-			us_test av_mm_writeda						00200400h		1111					111111	ππ
-			us_test ipbus_ctrl:ipbu		01	ooh			1111040011					oh			
			us test ipbus_ctrl:ipbu					ooh					ooh a in a				
			test[MACip:MACip 1]ff														-
			test[MACip:MACip_1]ff														-
			test[MACip:MACip_1]ff			_		1									-

Read chronogram of 64 words of 32bits with IP-BUS

(current implementation that can be optimized)

takes ~128 to be received + 256 clk to transfer from Avalon to IP-BUS then, unit 576 to be completely sent to the Ethernet mac => 704 clk for 64 (32bits)*4 bytes => 704 for 256bytes.

256/0.0000176 => ~14.5Mbyte/s (without CPU/driver induced delays)



Firmware – BWS-FW1 - IP-BUS link to SW

ID	h	us
	υ	นอ

User's guide Developer's guide Admin (restricted)

Software and firmware that provide a reliable high-performance control link for particle physics electronics, by implementing a simple A32/D32 control protocol for reading and modifying memory-mapped resources within FPGA-based hardware devices.

Introduction to IPbus User's gu

Firmware

Repository (GitHub): ipbus/ipbus-firmware Version: v1.8

Latest updates:

- Firmware v1.8 released
 Thu, 30 Apr, 2020
- Firmware v1.7 released Mon. 3 Feb. 2020
- Firmware v1.6 released
- Tue, 22 Oct, 2019

Software

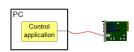
Repository (GitHub): ipbus/ipbus-software Version: v2.7.5

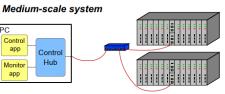
Latest updates:

- Software v2.7.5 released Thu. 11 Jun. 2020
- Software v2.7.4 released
- Fri, 15 May, 2020
- Software v2.7.3 released Sat, 21 Mar, 2020

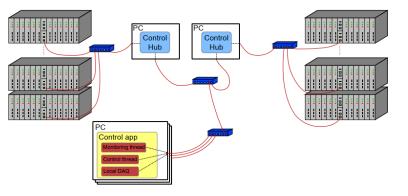
Publication

C. Ghabrous Larrea, K. Harder, D. Newbold, D. Sankey, A. Rose, A. Thea and T. Williams, "IPbus: a flexible Ethernet-based control system for xTCA hardware", JINST **10** (2015) no.02, C02019. DOI: 10.1088/1748-0221 /10/02/C02019 Small-scale system





Large-scale system



1-to-1 block transfers. The block read/write latency and throughput for one μ HAL client controlling one device via the ControlHub is shown in figure 2. The median single-word write/read latency is approximately $250 \,\mu$ s. Although this single-word latency is significantly larger than with VME/PCIe-based control, for multiple transactions or large block transfers this is compensated by concatenating multiple transactions into each packet, and by having multiple packets in flight around the system at any given time. Together, concatenation and multiple packets in flight increase throughput by a factor of approximately 20 to 2000, depending on transaction type. Hence, the 1-to-1 block read/write throughput for payloads larger than 1 MByte is above 0.5 Gbit/s.

http://ipbus.web.cern.ch/ipbus/



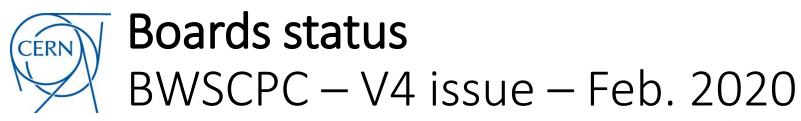
- Implementation on-going of the scan sequencer to hide low level HW control from the SW
- Handling of the power stage of the electronics
- Generation of signal synchro for the acquisition electronics
- Time stamping scanner events for the SW

IdMcOperationModeExpert IdMotionSequencerCurrentStep IdMotionSequencerLastExitSte clk i IdMotionSequencerLastExitStepTim IdMcOperationModeExpert IdMotionSequencerLastScanResul IdTriggerScanImmediate_ IdMotionSequencerRequestScan_i IdTriggerScanExternal IdTriggerScanImmediate_i IdTriggerScanOptical_ IdPwmOutputEnable IdTriggerScanExternal_i IdTriggerScanOptical_i lPwmOutputEnable lPwmw IdPwmu [dPwmv_ Top LIU–BWS sequencer dPwmu dInverterControlSpiPayload16_i IdInverterControlSpiPayload1 IdPositionWhenLastInScanStarte dSfixedMpmtAcqTriggerAngleInScanStart IdPositionWhenLastOutScantStrarteIdAppliedInOutTimingLastSca lSfixedMpmtAcqTriggerAngleInScanStop SfixedMpmtAcqTriggerAngleOutScanStart IdMpmtAcqTimeStampInScanStar lSfixedMpmtAcqTriggerAngleOutScanStopIdMpmtAcqTimeStampInScanStop IdMpmtAcqTimeStampOutScanStar dResolverPositionIntegrated IdMpmtAcqTimeStampOutScanStop IdMpmtAcqAngleInScanStar dResolverSetPosition dCurrentPhaseU IdMpmtAcqAngleInScanStop dCurrentPhaseV IdMpmtAcqAngleOutScanStar dCurrentPhaseW IdMpmtAcqAngleOutScanStop



Additional slides

LIU BWS - electronics & systems - 15.09.2020



Problem:

- Systematic components burning (at least 6 times) Flyback shunt, MOSFET and driver
- Happens after few seconds of operation
- Only when controlled by BWS-MIB

Actions:

- CPC design dimensioning re-checked
- MOSFET switching characteristics extensively measured
- Multiples board modifications tested:

 Better grounding large ground bounces
 Increasing shunt resistor lowering charge current
 Gate resistor to slow down MOSFET slew rate
- Suspecting EMI inducing instabilities on the control signals
- Sum of design flaws are leads to this situation



